



Image

Attorney's Docket No.: 10559-591001 (P12772)

2878

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Alan Wong et al.

Art Unit : 2878

Serial No. : 10/083,877

Examiner : David C. Meyer

Filed : February 25, 2002

Title : OPTICAL METROLOGY TARGET DESIGN FOR SIMULTANEOUS  
MEASUREMENT OF MULTIPLE PERIODIC STRUCTURES

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

TRANSMITTAL LETTER

Correspondence relating to this application is enclosed. The required fees are computed below. Please apply any charges not covered, or any credits, to Deposit Account No. 06-1050.

Total Claims	81	-	90	=	0	\$0
Independent	5	-	4	=	1	\$86
First Presentation of Multiple Dependent Claims						\$0

Applicant hereby petitions under 37 C.F.R. §1.136 for a 0 month extension of time.

\$0

TOTAL FEE DUE

\$86

A check for \$86 is attached.

Respectfully submitted,

Date: February 9, 2004

Scott R. Boalick  
Reg. No. 42,337

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**AMENDMENT IN REPLY TO ACTION OF NOVEMBER 7, 2003**

Please amend the above-identified application as follows:

Amendments to the claims are reflected in the listing of claims, which begins on page 2  
of this paper.

Remarks begin on page 14 of this paper.

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